

AMENDMENTS TO THE SPECIFICATION

Please replace paragraph [0042] with the replacement paragraph set forth below.

[0042] The measurement of the thickness and indices of refraction of layers 74-78 and of the grating parameters may be performed together or separately as described in PCT/US99/04053, Publication No. WO 99/45340, filed February 25, 1999, entitled "~~Spectroscopic Scatterometer System~~ Measuring a Diffracting Structure, Broadband, Polarized, Ellipsometric, and an Underlying Structure," which is incorporated herein by reference in its entirety.

Please replace paragraph [0055] with the replacement paragraph set forth below.

[0055] As noted above, optical components 106 and 120 may be polarizers or compensators such as wave plates. One or both components 106 and 120 may be stationary or rotating depending on the amount of information that is desired. Thus, there may be a wide variety of different embodiments that may be constructed from the overall configuration of Fig. 3, depending on whether one or both of the optical components 106, 120 is stationary or rotating and whether they are polarizers or compensators or various combinations. Optical components 106 and 120 may also comprise multiple polarizers and/or compensators. These various combinations are described in more detail in ~~PCT/US00/65331~~ PCT/US00/10875, Publication No. WO 00/65331 filed April 21, 2000, entitled "System for Analyzing Surface Characteristics with Self-Calibrating Capability," which is incorporated by reference in its entirety.